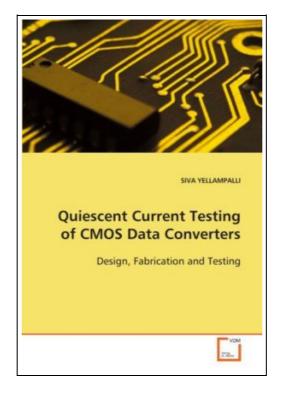
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Reviews

It is fantastic and great. This is for those who statte there was not a worth looking at. Its been written in an exceptionally easy way which is only soon after i finished reading this ebook through which in fact changed me, change the way i really believe.

(Barry O'Reilly)

QUIESCENT CURRENT TESTING OF CMOS DATA CONVERTERS



VDM Verlag Feb 2009, 2009. Taschenbuch. Book Condition: Neu. 220x150x7 mm. Neuware - 1999 fand anlässlich des 70. Geburtstages von JürgenHabermas ein Symposion an der Johann WolfgangGoethe-Universität statt, in dem speziell die Aspekteseines Werkes diskutiert wurden, die das Verhältnisvon Rechtfertigung und Wahrheit bzw. Richtigkeitbetreffen. Diese Beiträge wurden in dem Band 'DieÖffentlichkeit der Vernunft und die Vernunft derÖffentlichkeit' publiziert. Darin findet sich aucheine kritische Auseinandersetzung des amerikanischenPhilosophen Hilary W. Putnam mit der Moraltheorie von Jürgen Habermas. Putnam kritisiert die dichotomeTrennung von Werten und Normen in der Diskursethik, aus der letztlich das Problem entstehe, dass entwederdie in der Diskursethik generierten Normen keinenuniversellen Status erlangen könnten oder dieTrennung zwischen Wert und Norm selbst unhaltbar sei. Aus dieser Kritik entwickelt sich in der Folgezeiteine Debatte um die Frage nach dem Verhältniszwischen Norm und Wert. Die vorliegende Arbeit führt in diemoralphilosophischen Grundpositionen von Habermas und Putnam ein, stellt die spezifische Problematik derDebatte dar und erörtert und einige Lösungsperspektiven. Power supply quiescent current (IDDQ) testing has been very effective in detecting physical defects such as open, short and bridging defects in VLSI circuits designed in CMOS processes. However, in submicron VLSI circuits, IDDQ current is masked by the increased subthreshold (leakage) current of MOSFETs affecting the efficiency of IDDQ testing. In this work, an attempt has been made to perform robust IDDQ testing in presence of increased leakage current by suitably modifying some of the test methods normally used in industry. In this book we have re-examined both IDDQ and Delta IDDQ methods of testing CMOS VLSI circuits and added features to minimize the influence of leakage current. We have designed built-in current sensors (BICS) for on-chip testing of analog and mixed-signal integrated circuits. We have also combined quiescent current testing with oscillation and transient current techniques to map large number of manufacturing defects on a chip. 116 pp. Deutsch.



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